

Notice of References Cited	Application/Control No. 10/560,405		Applicant(s)/Patent Under Reexamination CHARTIER ET AL.	
	Examiner John L. Goff		Art Unit 1791	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,251,219	06-2001	Chen et al.	156/556
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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